# MOS FIELD EFFECT TRANSISTOR **2SK1824**

# N-CHANNEL MOS FET FOR SWITCHING

The 2SK1824 is a N-channel vertical type MOS FET that is driven at 2.5 V.

Because this MOS FET can be driven on a low voltage and because it is not necessary to consider the drive current, the 2SK1824 is ideal for driving the actuator of power-saving systems, such as VCR cameras and headphone stereo systems.

Moreover, the 2SK1824 is housed in a super small mini-mold package so that it can help increase the mounting density on the printed circuit board and lower the mounting cost, contributing to miniaturization of the application systems.

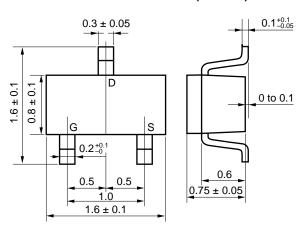
### **FEATURES**

NEC

- Small mounting area: about 60 % of the conventional mini-mold package (SC-70)
- Can be automatically mounted
- Can be directly driven by 3-V IC

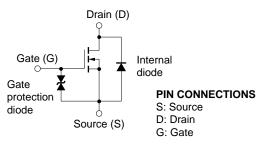
The internal diode in the right figure is a parasitic diode.

The protection diode is to protect the product from damage due to static electricity. If there is a danger that an extremely high voltage will be applied across the gate and source in the actual circuit, a gate protection circuit such as an external constant-voltage diode is necessary.



PACKAGE DIMENSIONS (in mm)

### EQUIVALENT CIRCUIT



Marking: B1

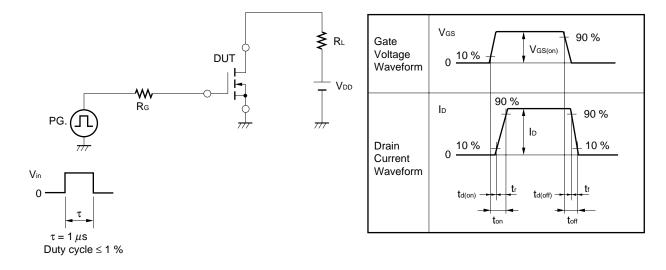
PARAMETER	SYMBOL	TEST CONDITIONS	RATING	UNIT
Drain to Source Voltage	Vdss	V <sub>GS</sub> = 0	30	V
Gate to Source Voltage	Vgss	V <sub>DS</sub> = 0	±7	V
Drain Current (DC)	ID(DC)		±100	mA
Drain Current (Pulse)	D(pulse)	$PW \le 10 ms$ Duty cycle $\le 50 \%$	±200	mA
Total Power Dissipation	P⊤	$3.0\ \mbox{cm}^2 \times 0.64\ \mbox{mm},$ ceramic substrate used	200	mW
Channel Temperature	Tch		150	°C
Operating Temperature	Topt		-55 to +80	°C
Storage Temperature	Tstg		-55 to +150	°C

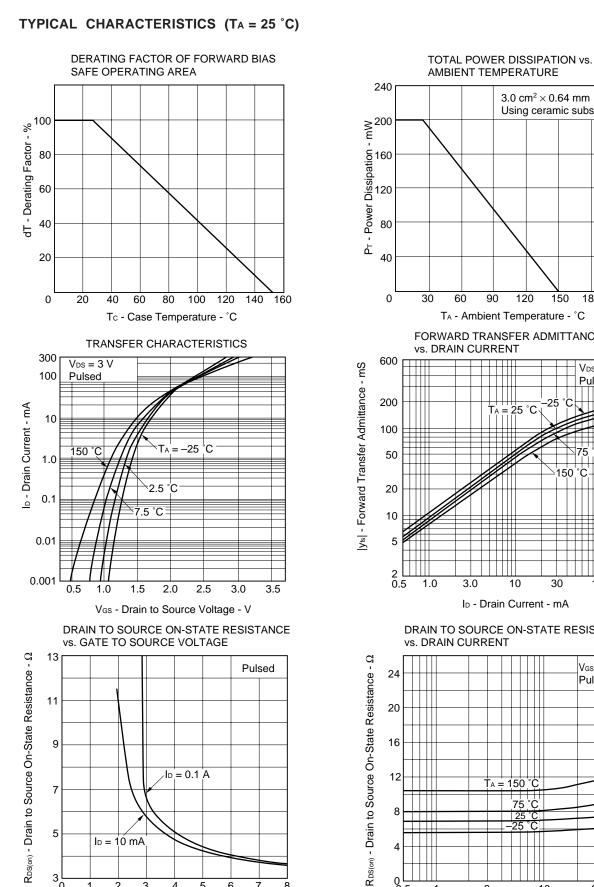
### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 $^{\circ}$ C)

ELECTRICAL	CHARACTERISTICS	(T <sub>A</sub> = 25 °C)
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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain Cut-Off Current	loss	$V_{DS} = 30 V, V_{GS} = 0$			1.0	μΑ
Gate Leakage Current	lgss	$V_{GS} = \pm 5 V$ , $V_{DS} = 0$		±0.1	±3	μA
Gate Cut-Off Voltage	VGS(off)	$V_{DS} = 3 V, I_{D} = 10 \mu A$	0.8	1.0	1.5	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 3 V, I <sub>D</sub> = 10 mA	20	50		mS
Drain to Source On-State Resistance	RDS(on)1	Vgs = 2.5 V, Id = 1 mA		7	13	Ω
Drain to Source On-State Resistance	RDS(on)2	Vgs = 4.0 V, Id = 10 mA		5	8	Ω
Input Capacitance	Ciss	V <sub>DS</sub> = 5.0 V, V <sub>GS</sub> = 0, f = 1 MHz		16		pF
Output Capacitance	Coss			14		pF
Reverse Transfer Capacitance	Crss			2		pF
Turn-On Delay Time	td(on)	$V_{DD} = 5V, I_D = 10 \text{ mA}$		15		ns
Rise Time	tr	$V_{GS(on)} = 5 V, R_G = 10 \Omega$		20		ns
Turn-Off Delay Time	td(off)	RL = 500 Ω		100		ns
Fall Time	tr			100		ns

## SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS (Resistive Load)



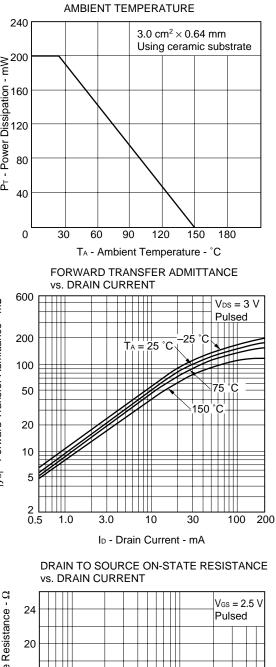


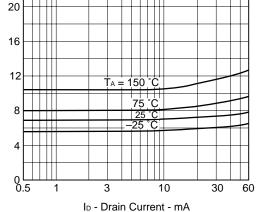
ID = 0.1 A

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 $I_D = 10 \text{ mA}$ 

Vgs - Gate to Source Voltage - V



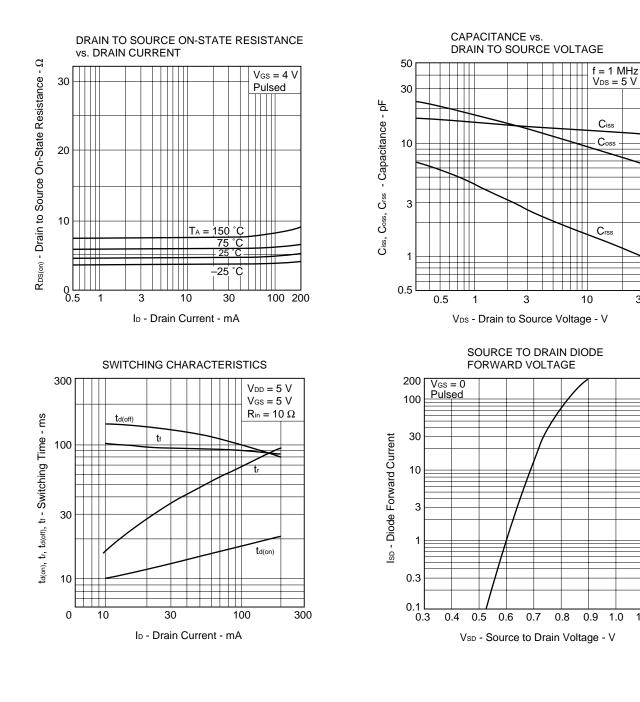


Ciss Coss

 $C_{\text{rss}}$ 

1.0 1.1

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# REFERENCE

Document Name	Document No.		
NEC semiconductor device reliability/quality control system	TEI-1202		
Quality grade on NEC semiconductor devices	IEI-1209		
Semiconductor device mounting technology manual	C10535E		
Guide to quality assurance for semiconductor devices	MEI-1202		
Semiconductor selection guide	X10679E		

[MEMO]

NEC

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Anti-radioactive design is not implemented in this product.

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